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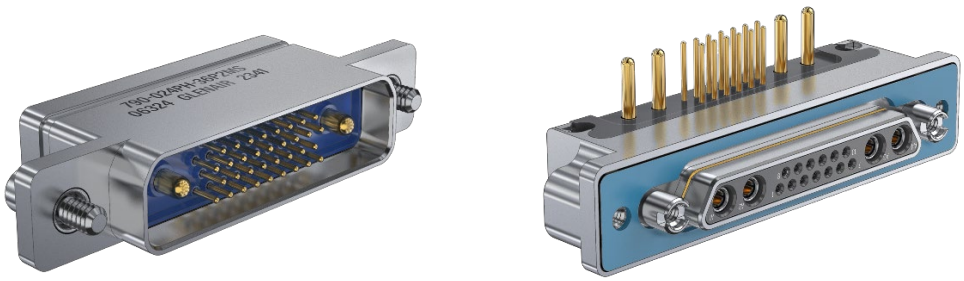
QUALIFICATION TEST REPORT ABSTRACT
FOR
GLENAIR SERIES 79
MICRO-CRIMP CONNECTORS

REPORT NO. GT-24-099 ABSTRACT



SERIES 79 MICRO-CRIMP CONNECTORS

PREPARED BY: Ryan O'Shea DATE: 2/13/26

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UPDATED BY: _____ DATE: _____

1.0 Product Description/Application

Lightweight, high-density Series 790 combines a small form-factor Micro-D M83513-style shell with M39029-type crimp or PC tail contacts. Crimp contacts are snap-in, rear release. 42 insert arrangements with up to 153 size #23 contacts. EMI protected with ground spring and conductive panel gasket. Environmental, with fluorosilicone face seal and wire grommet.

1.1 Purpose

Testing was performed on 44 Series 79 micro-crimp connectors to determine its conformance to the performance requirements of mechanical, environmental, electrical performance requirements outlined in the Glenair series micro-crimp connector procedure of product performance specification.

1.2 Scope

This report summarizes the environmental, mechanical and electrical qualification testing of Series 79 micro-crimp connectors. The information in this report was obtained from tests conducted by DNB Engineering. The documents listed below are on file at Glenair and are available upon request.

Applicable Test Reports		
Test Report Number	Provider	Date Tested
GT-24-099	Glenair	02-13-23 to 05-03-24
TR047724	DNB Engineering Inc.	02-13-23 to 05-03-24

1.3 Conclusion

Series 79 Micro Crimp Connectors has been shown to be capable of meeting performance requirements.

1.4 Test Specimens

Test Sample Description	
Group 1	
Description	Part Number
Receptacle Connector Cable, 5 Pin. (23 GA)	790-024PA-5ML
Plug Connectors Cable, 5 Socket. (23 GA)	790-025SA-5EMP
Receptacle Connector Cable, 5 Pin. (16 GA)	790-024PF-5P5ML
Plug Connector Cable , 5 Socket. (16 GA)	790-025SF-5P5EMP
Receptacle Connector, PCB, Panel MT (12 GA)	790-036PL-6P6MPA
Plug Connector Cable, 6 socket. (12 GA)	790-025SL-6P6EML

Test Sample Description	
Group 2	
Description	Part Number
Plug Connector, Cable, 5 Pin (23 GA)	790-025SA-5EML
Receptacle Connectors, Cable 5 Socket (23 GA)	790-024PA-5MP
Plug Connectors, Cable 5 Socket (16 GA)	790-025SF-5P5EML
Receptacle Connector, Cable 5 Pin (16 GA)	790-024PF-5P5MP
Receptacle, R/A PCB MT 6 Pin (12 GA)	790-036PL-6P6MPA
Plug Connector, Cable, 6 socket (12 GA)	790-025SL-6P6EML
Receptacle Connector, PCB, 5 Pin (23 GA)	790-028PA-5MPA
Plug Connector, Cable, 5 socket (23 GA)	790-025SA-5EML

Test Sample Description	
Group 3	
Description	Part Number
Receptacle Connector, Cable 5 Pin (23 GA)	790-024PA-5ML
Plug Connector, Cable 5 Socket (23 GA)	790-025SA-5EMP
Receptacle Connector, cable 5 Pin (16 GA)	790-024PF-5P5ML
Plug Connector, Cable 5 Socket (16 GA)	790-025SF-5P5EMP
Receptacle Connector, Cable 5 Pin (16 GA)	790-024PF-5P5ML
Plug Connector, Cable 5 Socket (16 GA)	790-025SF-5P5EMP
Receptacle Connector, Cable 5 Pin (16 GA)	790-024PF-5P5ML
Plug Connector, Cable 5 Socket (16 GA)	790-025SF-5P5EMP
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Plug Connector, Cable 5 Socket (16 GA)	790-025SF-5P5EML
Receptacle Connector, Cable 5 Pin (16 GA)	790-024PF-5P5MP
Plug Connector, Cable 5 Socket (16 GA)	790-025SF-5P5EML

Test Sample Description	
Group 4	
Description	Part Number
Receptacle Connector, Cable 5 Pin (16 GA)	790-024PF-5P5MP
Plug Connector, Cable 5 Socket (16 GA)	790-025SF-5P5EML
Receptacle Connector, Cable 5 Pin (16 GA)	790-024PF-5P5MP
Plug Connector, Cable 5 Socket (16 GA)	790-025SF-5P5EML

Test Sample Description	
Group 5	
Description	Part Number
Receptacle Connector Straight PCB 5 Pin (23 GA)	790-028PA-5MNA
Plug Connector, R/A PCB 5 Socket (23 GA)	790-037SA-5MENA
Receptacle Connector, Straight PCB 5 Pin (23 GA)	790-043PA-5MNA
Plug Connector, R/A PCB 5 Socket (23 GA)	790-042SA-5MENA

1.5 Inspection Procedure

All tests were performed with the test specimen at standard laboratory conditions and within procedural parameters as defined below.

1. Ambient room temperature: 25°C ± 10°C (77°F ± 18°F)
2. Relative humidity: Room ambient up to 90% relative
3. Barometric pressure: Prevailing room conditions

2.0 Qualification Test Summary

Qualification Test		
Group 1		
Test Name	QTP-1199 Test Paragraph	Test Sample S/N Complete
Visual Inspection	5.2	001 - 006
Mechanical Inspection	5.2	001 - 006
Magnetic Permeability	5.3	001 - 006
Temperature Cycling	5.5	001 - 006
Durability	5.6	001 - 006
Altitude Immersion	5.7	001 - 006
Insulation Resistance Ambient Temperature	5.8	001 - 006
Dielectric Withstanding Voltage (Sea Level)	5.9	001 - 006
Insert Retention	5.10	001- 006
Shell-to-Shell Conductivity	5.17	001 - 006
Salt Spray	5.11	001 - 006
Shell-to-Shell Conductivity	5.17	001 - 006

Post Test Examination	5.26	001 - 006

Qualification Test		
Group 2		
Test Name	QTP-1199 Test Paragraph	Test Sample S/N Complete
Visual Inspection	5.2	007 - 014
Mechanical Inspection	5.2	007 - 014
Low Level Contact Resistance	5.23	007 - 014
Contact Resistance	5.12	007 - 014
Mating and Un-mating Force	5.4	007 - 014
Contact Retention	5.13	007 - 014
Altitude – Low Temperature	5.14	007 - 014
Insulation Resistance Ambient Temperature	5.8.1	007 - 014
Dielectric Withstanding Voltage (Sea Level)	5.9	007 - 014
Insulation Resistance Elevated Temperature	5.8.2	007 - 014
Durability	5.6	007 - 014
Vibration	5.15	007 - 014
Shock	5.16	007 - 014
Shell to Shell Conductivity	5.17	007 - 014
Humidity	5.18	007 - 014
Insulation Resistance Ambient Temperature	5.8.1	007 - 014
Dielectric Withstanding Voltage (Sea Level)	5.9	007 - 014
Post Test Examination	5.26	007 - 014

Qualification Test		
Group 3		
Test Name	QTP-1199 Test Paragraph	Test Sample S/N Complete
Visual Inspection	5.2	015 - 036
Mechanical Inspection	5.2	015 - 036
Water Immersion	5.25	015 - 016
Fluid Immersion	5.20	017 - 036
Mating and Un-mating Force	5.4	015 - 016
Dielectric Withstanding Voltage (Sea Level)	5.9	017 - 036
Post Test Examination	5.26	015 - 016

Qualification Test		
Group 4		
Test Name	QTP-1199 Test Paragraph	Test Sample S/N Complete
Visual Inspection	5.2	037 - 040
Mechanical Inspection	5.2	037 - 040
Shielding Effectiveness	5.19	037 - 040

Qualification Test		
Group 5 (PC Tail Not Wired)		
Test Name	QTP-1199 Test Paragraph	Test Sample S/N Complete
Visual Inspection	5.2	041 - 044
Mechanical Inspection	5.2	041 - 044
Current Rating	5.24	041 - 044
Solderability	5.21	041, 042
Resistance to Solder Heat	5.22	043, 044
Insulation Resistance Ambient Temperature	5.8.1	041 - 044
Post Test Examination	5.26	041 - 044

All test samples passed per requirements. Data and test setup photos are in the environmental test completion summary of results DNB Engineering Inc.

5.0 Test Verification

Except as otherwise specified for shielded contacts, wiring of crimp-type contacts shall be accomplished using tools conforming to MIL-DTL-22520, class I. The length of the stripped portion of the conductor shall be at least long enough to reach the bottom of the crimp barrel but shall not be so long that more than .010 inch of the conductor is exposed at the end of the barrel when the conductor end touches the bottom of the barrel.

5.1 **Qualification Test Groups**

See Test Specimens

5.2 **Visual and Mechanical Examination**

5.2.1 Test Method

The connectors, accessories, and piece parts shall be visually and mechanically examined to ensure conformance with the specification and the applicable military standards

5.2.2 Requirement

The contractor may use in-process controls to satisfy these requirements. Perform a visual and mechanically inspection test using a magnifying glass or microscope device having magnification power of approximately 3X.

5.2.3 Results
PASS. No errors or failures exhibited.

5.2.4 Test Anomalies/Deviations
N/A

5.3 Magnetic Permeability

5.3.1 Test Method
Connectors shall be tested in accordance with test procedure EIA-364-54.

5.3.2 Requirement
The relative permeability of the wired, assembled, and fully mated connector assemble shall be less than 2.0μ when measured in accordance with Table 3.

5.3.3 Results
PASS. No errors or failures exhibited.

5.3.4 Test Anomalies/Deviations
N/A

5.4 Mating and Unmating Forces

5.4.1 Test Method
The force for mating and unmating of counterpart connectors shall be tested in accordance with test procedure EIA-363-13.

Mating and Unmating Forces	
Axial Force (LBS)	
MAX. Mating Force	MIN. Un-mating Force
6LBS for Ground Spring +	3LBS for Ground Spring +
Number of 23 Gauge Contacts x .50 LBS +	Number of 23 Gauge Contacts x .047 LBS +
Number of 16 Gauge Contacts x 1.88 LBS +	Number of 16 Gauge Contacts x .125 LBS +
Number of 12 Gauge Contacts x 1.88 LBS =	Number of 12 Gauge Contacts x .187 LBS =
Total Mating Force	Total Unmating Force

5.4.2 Requirement
The connectors used in this test shall have the complement of contacts.

5.4.3 Results
PASS. No errors or failures exhibited.

5.4.4 Test Anomalies/Deviations
N/A

5.5 Temperature Cycling

5.5.1 Test Method
Unmated connectors shall be subjected to 5 temperature cycles per EIA-364-32

5.5.2 Requirement
Test Condition VI Method A from -65°C to 150°C:

5.5.3 Results
PASS. No errors or failures exhibited.

5.5.4 Test Anomalies/Deviations
N/A

5.6 Durability

5.6.1 Test Method
Connectors shall be tested in accordance with EIA-364-09

5.6.2 Requirement
The wired, assembled plugs and receptacles shall be mated and unmated 500 cycles. The mating and unmating shall be accomplished so that the plug and receptacle are completely separated during each cycle.

5.6.3 Results
PASS. No errors or failures exhibited.

5.6.4 Test Anomalies/Deviations
N/A

5.7 Altitude Immersion

5.7.1 Test Method
Mated connectors shall be tested in accordance with test procedure EIA-364-03.

5.7.2 Requirement
- All wire ends shall be located within the chamber and exposed to the chamber atmosphere but not submerged or sealed.
- Maximum wire size shall be used per table VIII.
- At the end of the third cycle while the connectors are still submerged in the solution 75,000 feet simulated altitude the insulation resistance at ambient temperature shall be measured as specified in 5.8.1 and the dielectric withstanding voltage test shall be performed as specified in 5.9.1.

5.7.3 Results
PASS. No errors or failures exhibited.

5.7.4 Test Anomalies/Deviations
N/A

5.8 Insulation Resistance

5.8.1 Test Method
Insulation resistance at ambient temperature.

- Unmated connectors shall be tested in accordance with test procedure EIA-364-21. The following details and exceptions apply:
- For lot acceptance testing, where it is undesirable to install actual contacts in connectors, simulated contacts and special techniques may be used in performing this test.500 VDC ± 50 Volts. Test between adjacent contacts and contact to shell.
- Connectors shall be mated when testing after altitude immersion, humidity and altitude low temperature.

5.8.2 Requirement
Insulation Resistance at Elevated Temperature.

- Unmated connectors shall be tested in accordance with test procedure EIA-364-21. The following details and exceptions shall apply:
  - 500 VDC ± 50 Volts. Test between adjacent contacts and contact to shell.
  - Applicable elevated temperature for 30 minutes: 150°C +5°C/-0°C
  - Measurements shall be made while the connectors are still in the chamber at the specified temperature.

5.8.3 Results
PASS. No errors or failures exhibited.

5.8.4 Test Anomalies/Deviations
N/A

5.9 Dielectric Withstanding Voltage

5.9.1 Test Method
Wired, mated or unmated connectors shall be tested in accordance with test procedure EIA-364-20 method A. Connectors shall be mated when testing after altitude immersion humidity, and altitude low temperature.

5.9.2 Requirement
The magnitude of the test voltage shall be as specified in the table below.

- Test Voltages, AC RMS, 60 Hz

Test Voltages	
Contact Size	Test Voltage
#23 Gauge	750
#16 Gauge	1800
#12 Gauge	1800
#23 Gauge	750

- Fifty percent of the contacts available shall be tested, but in no case shall less than six dielectric withstanding voltage readings be taken. The test voltage shall be applied between each wired contact, and each adjacent contact, and the shell.
- The test voltage shall be maintained at the specified value for 2 seconds minimum.
- For quality conformance, simulated contacts and special techniques may be used in performing this test between each wired contact and each adjacent contact and the shell.

5.9.3 Results
PASS. No errors or failures exhibited.

5.9.4 Test Anomalies/Deviations
N/A

5.10 Insert Retention

5.10.1 Test Method
Unmated connectors shall be tested in accordance with test procedure EIA-364-35 at 50 ± 5 LBS.

5.10.2 Requirement

Follow chart for applicable load.

Insert Size	Area LBS/Inch	Load
A	.067 IN	3.7 LBS
F	.251 IN	13.8 LBS
K	.433 IN	23.8 LBS

5.10.3 Results
PASS. No errors or failures exhibited.

5.10.4 Test Anomalies/Deviations
N/A

5.11 Salt Spray (Corrosion)

5.11.1 Test Method
Mated connectors shall be tested in accordance with test procedure EIA-364-26 (Test Condition B), IEC 60512-11-6, with 5% salt solution at 35° C.

5.11.2 Requirement

The following details and exceptions shall apply:

- Group 1 shall be tested for 48 hours.
- Wire ends must be protected to prevent salt migration.

5.11.3 Results

PASS. No errors or failures exhibited.

5.11.4 Test Anomalies/Deviations

N/A

5.12 Contact Resistance

5.12.1 Test Method

Connectors shall be tested in accordance with test procedure EIA-364-06.

5.12.2 Requirement

Shall meet the contact resistance requirements in table 5. Appropriate compensation may be made for resistance in the measured value which is due to an additional length of wire included in the measurement.

Measurement		
Max Wire Size	Test Current	Voltage Drop
12	23	42
14	17	40
16	13	49
20	7.5	55
22	5	73
24	3	45
26	2	52
28	1.5	54

5.12.3 Results

PASS. No errors or failures exhibited.

5.12.4 Test Anomalies/Deviations

N/A

5.13 Contact Retention

5.13.1 Test Method

Contact retention shall be tested in accordance with test procedure EIA-364-29.

5.13.2 Requirement

Procedure I.

Contact retention shall be tested in accordance with test procedure EIA-364-29. The following details and exceptions shall apply:

- Number of samples - The test shall be performed on 20 percent of the contact complement; but not less than three contacts in each connector half.
- Applied axial load - Preload to 3 pounds maximum, (13.6 Newtons). Apply load as specified in table 6.
- Axial direction - The applicable forces shall be applied along the longitudinal axis of individual contacts in the direction tending to displace the contacts to the rear.
- Only the contacts to be tested need be installed in the connector.

Contact Retention		
Contact	Load ± 10 Percent	
	Min. Pounds	Min. Newtons
23	6	27
20	15	67
16	25	111
12	25	111

Procedure II.
Contact retention shall be tested in accordance with test procedure EIA-364-29. The following details and exceptions shall apply:

- 4.4.9.1a through 4.4.9.1c apply.
- Axial direction - Same as 4.4.16.1d, except the direction shall tend to displace the contacts to the front.
- Only the contacts to be tested need be installed in the connector.

5.13.3 Results
PASS. No errors or failures exhibited.

5.13.4 Test Anomalies/Deviations
N/A

5.14 Altitude-Low Temperature

5.14.1 Test Method
Wired, mated, assembled connectors shall be tested in accordance with test procedure EIA-364-105.

5.14.2 Requirement
The following details apply:

- No wire ends or splices inside the chamber.
- Chamber pressure shall be reduced to simulate approximately 40,000 feet altitude (141.2 Torr).
- 625V rms, 60Hz shall be 450V rms.
- Insulation resistance test to be performed at 100,000 feet at -65°C and shall be in accordance with 5.8.1.
- Dielectric withstanding voltage test to be performed after return to ambient conditions and shall be in accordance with 5.9.1.

5.14.3 Results
PASS. No errors or failures exhibited.

5.14.4 Test Anomalies/Deviations
N/A

5.15 Vibration

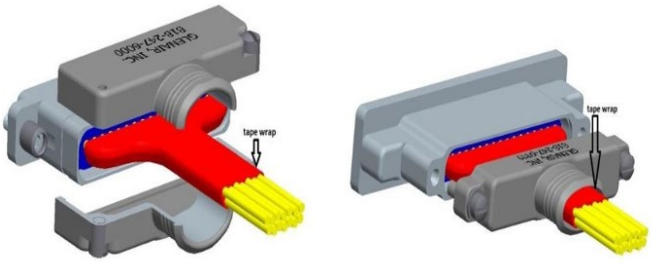
5.15.1 Test Method

- Sine Vibration. Testing shall be per EIA-364-28 test condition IV, at a frequency of 10 – 2,000 Hz. The amplitude shall be 20 G. At 196 m/s.
- Random Vibration. Connectors shall be tested in accordance with test procedure EIA-364-28 test condition V letter E, at a frequency of 50 – 2,000 Hz.

5.15.2 Requirement

All contacts shall carry a test current of 100 milliamperes maximum and shall be monitored for no discontinuities in excess of 1 microsecond. No cracking, breaking or loosening of parts. Plug shell cannot disengage from the receptacle. The below preparation of backshells required for all QTP-1199 vibration tests.

Vibration Preparation for Crimp Removable Wired Rectangular Connectors



Both these style backshells require the inner wires to be wrapped with silicone tape during assembly prior to random and sine vibration. The wire extending from the rear of backshell is to be clamped to the fixture and is to be as close as possible to the backshell.

5.15.3 Results
PASS. No errors or failures exhibited.

5.15.4 Test Anomalies/Deviations
N/A

5.16 Shock

5.16.1 Test Method
Connectors shall be tested in accordance with test procedure EIA-364-27 Condition D.

5.16.2 Requirements

- The pulse shall be an approximate half sine wave of 300 G ±15 percent magnitude with a duration of 3 ±1 milliseconds. 3 shocks x 3 axis x 2 directions = 18 shocks 2941 m/s (300G rms) 3m/s, half sine.
- The wire bundle shall be clamped to fixed points at least 8 inches (203.2 mm) from the rear of the connector in addition to having the wires clamped at the cable exit of the backshell.
- Backshell required with wire taped together and wrapped around backshell banding platform.

5.16.3 Results

PASS. No errors or failures exhibited.

5.16.4 Test Anomalies/Deviations

N/A

5.17 Shell-to-Shell Resistance

5.17.1 Test Method

Mated connectors shall be tested in accordance with test procedure EIA-364-83.

5.17.2 Requirement

When tested as specified in probes shall not puncture or otherwise damage the connector finish and the maximum measured potential drop across assemblies shall be 2.5 millivolts for plugs with spring EMI. After conditioning (salt spray) the above values may increase 100%.

5.17.3 Results

PASS. No errors or failures exhibited.

5.17.4 Test Anomalies/Deviations

N/A

5.18 Humidity

5.18.1 Test Method

Wired, mated connectors shall be tested in accordance with test procedure EIA-364-31 Test Condition IV.

5.18.2 Requirements

The following details and exceptions shall apply:

- The mated connectors shall be mounted in a horizontal position.
- Step 7a shall be performed during the last 5 cycles.
- Three hours minimum after the start of step 7a during the final cycle and while the connectors are still subjected to high humidity, insulation resistance and dielectric withstanding voltage shall be measured when the chamber temperature reaches 20°C ±5°C and condensation is observed on the connector.
- For qualification testing, insulation resistance readings shall be made on a minimum of 50% of the circuits. Outer circuits shall be measured to the connector shell.

5.18.3 Results
PASS. No errors or failures exhibited.

5.18.4 Test Anomalies/Deviations
N/A

5.19 EMI shielding

5.19.1 Test Method

- EMI shielding, Low Frequencies. Applicable frequency range is 100 to 1,000 MHz only. The EMI shielding effectiveness of mated connectors shall be measured using the mode-stirred technique in accordance with test procedure EIA-364-66.
- EMI Shielding, High Frequencies. Applicable frequency range is 1,000 to 10,000 MHz The EMI shielding effectiveness of mated connectors shall be measured using the mode-stirred technique in accordance with test procedure EIA-364-66.

5.19.2 Requirement

When tested as specified in the EMI shielding capabilities of mated shells with spring EMI shall not be less than that specified in table 7 at the specified frequencies.

EMI Shielding Effectiveness	
Frequency MHz	Leakage Attenuation (dB) Minimum
100	75
200	70
300	65
400	60
800	55
1000	50
1500	48
2000	46
3000	44
4000	41
6000	38
10000	35

5.19.3 Results
PASS. No errors or failures exhibited.

5.19.4 Test Anomalies/Deviations
N/A

5.20 Fluid immersion

5.20.1 Test Method
Connector samples shall be tested in accordance with test procedure EIA-364-10.

5.20.2 Requirement
Following the fluid immersion cycles, the dielectric withstanding voltage at sea level shall be tested in accordance with 5.9.1 within 3 hours.

5.20.3 Results
PASS. No errors or failures exhibited.

5.20.4 Test Anomalies/Deviations
N/A

5.21 Solderability

5.21.1 Test Method
Printed circuit tail terminations shall be tested in accordance with method EIA-364-52, Category 3, IEC-60512-12-1 and IEC-68-2-20 Test Table, method 1.

5.21.2 Requirement
Connectors will undergo 8 hours of steam aging prior to test at 245°C with a 4 to 5 second dwell and 10x magnification

5.21.3 Results
PASS. No errors or failures exhibited.

5.21.4 Test Anomalies/Deviations
N/A

5.22 Resistance to Solder Heat

5.22.1 Test Method
Unmated connectors with printed circuit tails shall be tested in accordance with EIA-364-56 and IEC-60512-12-5, Test 12e.

5.22.2 Requirement
Connectors shall be tested as follows:

- The test specimens shall be fluxed accordingly with flux liquid or other techniques.
- The solder iron shall be heated to a temperature of 360°C ±10°C and shall be applied to the termination for a period necessary to hold the solder in a liquid state for 4 to 5 seconds. Solder type to be used is Sn-63 in accordance with J-STD-006 or an equivalent industry standard.
- After application, the soldering iron shall be removed and a visual (10x magnification) and mechanical inspection performed.

5.22.3 Results
PASS. No errors or failures exhibited.

5.22.4 Test Anomalies/Deviations
N/A

5.23 Low Level Contact Resistance

5.23.1 Test Method
Test in accordance with EIA-364-23.

5.23.2 Requirement

100 milli-amperes maximum and 20 millivolts maximum open circuit voltage. The low level signal contact resistance of each mated contact pair shall not exceed the applicable values per Table 8, also specified in section 4.7.4 of Mil-C-39029.

Low Level Contact Resistance	
Wire Size	Max. Milliohms
12 & 16	5
20	9
22	15
24	20
26	31
28	50

5.23.3 Results
PASS. No errors or failures exhibited.

5.23.4 Test Anomalies/Deviations
N/A

5.24 Current Rating

5.24.1 Test Method
Respectively when tested in accordance with EIA-364-70 Method 1.

5.24.2 Requirement
The current rating of the #23 and #16 contacts shall be 5.0 amps and 13.0 amps.

5.24.3 Results
PASS. No errors or failures exhibited.

5.24.4 Test Anomalies/Deviations
N/A

5.25 Water Immersion

5.25.1 Test Method
Tested in accordance with MIL-STD-810F Method 512.4.

5.25.2 Requirement
There shall be no evidence of water penetration into mated connectors when subjected to MIL-STD-810F Method 512.4 (1 meter for 1 hour).

5.25.3 Results
PASS. No errors or failures exhibited.

5.25.4 Test Anomalies/Deviations
N/A

5.26 Post Test Examination

5.26.1 Test Method
The tested connectors and contacts shall be examined for compliance with 4.34 to determine the effects of previous testing.

5.26.2 Requirement
Any evidence of cracking, loosening of parts, carbon tracking, excess wear, or missing parts shall be recorded.

5.26.3 Results
PASS. No errors or failures exhibited.

5.26.4 Test Anomalies/Deviations
N/A